

SWS1130

Configurable 24-bit Capacitance-to-Digital Interface IC for High Performance Capacitive MEMS Accelerometer

General Description

The SWS1130 is a capacitive interface with a digital output for capacitive MEMS accelerometers. The SWS1130's configurable interface supports a wide range of MEMS accelerometers of various sensitivities that require a high resolution capacitive readout interface. The SWS1130 interfaces differential capacitors and is capable of sensing capacitance changes down to $50 \text{ zF}/\sqrt{\text{Hz}}$.

The SWS1130's capacitive front-end has a trimmable gain and offset to accommodate MEMS process variation during fabrication. The SWS1130 requires only a single 5V supply and few passive components.

The SWS1130 has an on-chip OTP and MTP to store trimming and calibration settings.

Features

- Ultra low noise capacitive detection front-end with resolution < 50zF/√Hz
- High resolution ADC offering more than 100dB dynamic range in 100HZ BW
- Configurable capacitive front-end to support different sensing element designs
- Charge pump for high voltage excitation option
- Second order scale factor and bias correction using on chip temperature sensor
- Tunable bandwidth output filter
- On chip clock generation
- Low noise reference voltage
- OTP/MTP for sensor trimming and recalibration
- Single 5V supply operation with 23mA supply current
- 10Mb/s standard SPI interface in slave mode
- Available in QFN56 package or in a bare die format

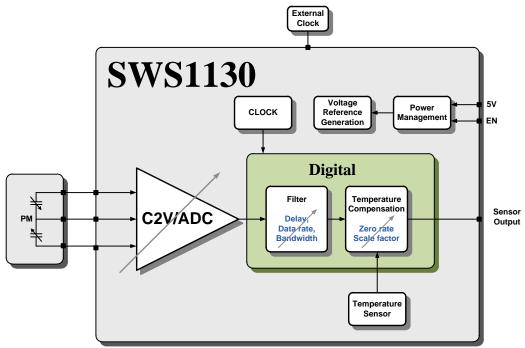
Applications

The SWS1130 is targeted at applications with low resolution requirements. Typical applications include:

- Industrial
- Navigation
- Inclinometers
- Motion and position measurements
- Seismic



Block Diagram



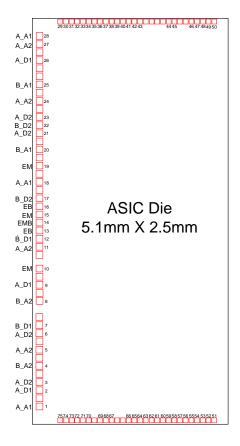
Specifications

Parameter	Conditions	Min	Тур	Max	Units
Front-End					
Supported Nominal Capacitance		0.25		15	pF
Differential Capacitance Range	Low-voltage operation			1.5	pF
	High-voltage operation			0.85	pF
Input Noise	At max gain setting, parasitic capacitance = 50pF		50		zF/√Hz
Linearity	At maximum voltage output	11			Bit
ADC Dynamic Range	In 100 BW		100		dB
Output					
Bandwidth		4		420	Hz
Group Delay		2		710	Ms
Output Resolution	Two's complement format		24		Bit
Supply Voltage		4.75	5	5.25	V
Complex Compant	Low-voltage operation		23		mA
Supply Current	High-voltage operation		29		mA
Power Down Current			1		μA
Operating Temperature Range		-40		85	°C



Bare Die and Pad-Out

Die dimensions are 5.1 mm by 2.5 mm and 300 μ m thickness. Pad openings are 60 μ m by 60 μ m with a pitch of 70 μ m on die north and south sides ball bonding to package pads. MEMS interfacing pads are arranged on one side (left) with a pad opening of 80 μ m by 80 μ m and a minimum pitch of 100 μ m. These MEMS side pads are designed to be compatible with both ball and wedge bonding process.



Pad Distribution on Die

MEMS Interface Pad Definitions

As shown in the following table SWS1130 provides two equivalent interface channels: channel-A and channel-B. Only one channel could be used to provide a single axis accelerometer interface. For compatibility with different MEMS pad arrangements, each channel can be configured for MEMS accelerometer capacitive output detection. Also, signals are represented at the MEMS interface by multiple pads to provide additional flexibility for MEMS pad location.

Pin No.	Name	Description
1	A_A1	Channel A +ve Actuation
2	A_D1	Channel A +ve Detection
3	A_D2	Channel A -ve Detection
4	B_A2	Channel B -ve Actuation
5	A_A2	Channel A -ve Actuation



6	A_D2	Channel A -ve Detection
7	B_D1	Channel B +ve Detection
8	B_A2	Channel B -ve Actuation
9	A_D1	Channel A +ve Detection
10	EM	Proof Mass
11	A_A2	Channel A -ve Actuation
12	B_D1	Channel B +ve Detection
13	EB	MEMS substrate
14	EMB	Inverted Proof Mass
15	EM	Proof Mass
16	EB	MEMS substrate
17	B_D2	Channel B -ve Detection
18	A_A1	Channel A +ve Actuation
19	EM	Proof Mass
20	B_A1	Channel B +ve Actuation
21	A_D2	Channel A -ve Detection
22	B_D2	Channel B -ve Detection
23	A_D2	Channel A -ve Detection
24	A_A2	Channel A -ve Actuation
25	B_A1	Channel B +ve Actuation
26	A_D1	Channel A +ve Detection
27	A_A2	Channel A -ve Actuation
28	A_A1	Channel A +ve Actuation

QFN Package

The main form of delivery of SWS1130 is bare die for integration in a single package with the MEMS sensing element. For applications that require packaged ICs, please contact SWS for QFN packaging options.



Revision History

Revision Date Description 0.1, September 2013

Revision	Date	Description
0.1	9-9-13	Original datasheet created

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